



C2M0160120D

Silicon Carbide Power MOSFET Z-FET™ MOSFET

N-Channel Enhancement Mode

Features

- High Speed Switching with Low Capacitances
- High Blocking Voltage with Low $R_{DS(on)}$
- Easy to Parallel and Simple to Drive
- Resistant to Latch-Up
- Halogen Free, RoHS Compliant

Benefits

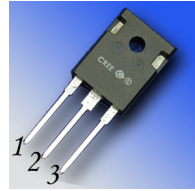
- Higher System Efficiency
- Reduced Cooling Requirements
- Increased System Switching Frequency

Applications

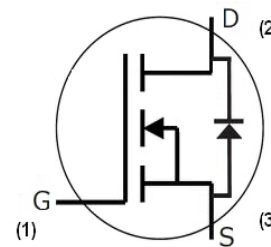
- Auxiliary Power Supplies
- Solar Inverters
- High Voltage DC/DC Converters
- High-frequency applications

| | |
|---------------------|--------|
| V_{DS} | 1200 V |
| $I_{D(MAX)}$ @ 25°C | 17.7 A |
| $R_{DS(on)}$ | 160 mΩ |

Package



TO-247-3



| Part Number | Package |
|-------------|----------|
| C2M0160120D | TO-247-3 |

Maximum Ratings ($T_C = 25^\circ\text{C}$ unless otherwise specified)

| Symbol | Parameter | Value | Unit | Test Conditions | Note |
|-----------------|--|-------------|--------------|---|---------|
| $I_{DS(DC)}$ | Continuous Drain Current | 17.7 | A | $V_{GS}@20\text{ V}, T_C = 25^\circ\text{C}$ | Fig. 19 |
| | | 11 | | $V_{GS}@20\text{ V}, T_C = 100^\circ\text{C}$ | |
| $I_{DS(pulse)}$ | Pulsed Drain Current | 45 | A | Pulse width $t_p = 50\ \mu\text{s}$ duty limited by $T_{jmax}, T_C = 25^\circ\text{C}$ | |
| V_{GS} | Gate Source Voltage | -10/+25 | V | | |
| P_{tot} | Power Dissipation | 125 | W | $T_C=25^\circ\text{C}$ | Fig. 20 |
| T_J, T_{stg} | Operating Junction and Storage Temperature | -55 to +150 | °C | | |
| T_L | Solder Temperature | 260 | °C | 1.6mm (0.063") from case for 10s | |
| M_d | Mounting Torque | 1 | Nm lbf-in | M3 or 6-32 screw | |
| | | 8.8 | | | |



Electrical Characteristics (T_C = 25°C unless otherwise specified)

| Symbol | Parameter | Min. | Typ. | Max. | Unit | Test Conditions | Note |
|----------------------|----------------------------------|------|------|------|------|---|--------------|
| V _{(BR)DSS} | Drain-Source Breakdown Voltage | 1200 | | | V | V _{GS} = 0 V, I _{DS} = 50 μA | |
| V _{GS(th)} | Gate Threshold Voltage | 2.0 | 2.5 | | V | V _{DS} = 10V, I _{DS} = 0.5 mA | Fig. 11 |
| | | 1.5 | 1.9 | | V | V _{DS} = 10V, I _{DS} = 0.5 mA, T _J = 150°C | |
| I _{DSS} | Zero Gate Voltage Drain Current | | 1 | 100 | μA | V _{DS} = 1200 V, V _{GS} = 0 V | |
| | | | 10 | 250 | | V _{DS} = 1200 V, V _{GS} = 0 V, T _J = 150°C | |
| I _{GSS} | Gate-Source Leakage Current | | | 0.25 | μA | V _{GS} = 20 V, V _{DS} = 0 V | |
| R _{DS(on)} | Drain-Source On-State Resistance | | 160 | 196 | mΩ | V _{GS} = 20 V, I _D = 10 A | Fig. 4, 5, 6 |
| | | | 290 | 400 | | V _{GS} = 20 V, I _D = 10A, T _J = 150°C | |
| g _{fs} | Transconductance | | 4.3 | | S | V _{DS} = 20 V, I _{DS} = 10 A | Fig. 7 |
| | | | 4.1 | | | V _{DS} = 20 V, I _{DS} = 10 A, T _J = 150°C | |
| C _{iss} | Input Capacitance | | 527 | | pF | V _{GS} = 0 V V _{DS} = 800 V f = 1 MHz V _{AC} = 25 mV | Fig. 16, 17 |
| C _{oss} | Output Capacitance | | 47 | | | | |
| C _{rss} | Reverse Transfer Capacitance | | 4 | | | | |
| E _{oss} | C _{oss} Stored Energy | | 15 | | | | μJ |
| t _{d(on)v} | Turn-On Delay Time | | 7 | | ns | V _{DD} = 800 V, V _{GS} = -5/20 V I _D = 10 A R _{G(ext)} = 0 Ω, R _L = 40 Ω Timing relative to V _{DS} | Fig. 27 |
| t _{fv} | Fall Time | | 7 | | | | |
| t _{d(off)v} | Turn-Off Delay Time | | 13 | | | | |
| t _{rv} | Rise Time | | 12 | | | | |
| R _G | Internal Gate Resistance | | 6.5 | | Ω | f = 1 MHz, V _{AC} = 25 mV | |

Built-in SiC Body Diode Characteristics

| Symbol | Parameter | Typ. | Max. | Unit | Test Conditions | Note |
|-----------------|-----------------------|------|------|------|---|-----------|
| V _{SD} | Diode Forward Voltage | 3.1 | | V | V _{GS} = -5 V, I _F = 5 A, T _J = 25 °C | Fig 9, 10 |
| | | 2.9 | | | V _{GS} = -2 V, I _F = 5 A, T _J = 150 °C | |

Thermal Characteristics

| Symbol | Parameter | Typ. | Max. | Unit | Test Conditions | Note |
|------------------|---|------|------|------|-----------------|---------|
| R _{θJC} | Thermal Resistance from Junction to Case | 0.9 | 1.0 | K/W | | Fig. 21 |
| R _{θCS} | Case to Sink, w/ Thermal Compound | 0.25 | | | | |
| R _{θJA} | Thermal Resistance From Junction to Ambient | | 40 | | | |

Gate Charge Characteristics

| Symbol | Parameter | Typ. | Max. | Unit | Test Conditions | Note |
|-----------------|-----------------------|------|------|------|--|---------|
| Q _{gs} | Gate to Source Charge | 6.9 | | nC | V _{DS} = 800 V, V _{GS} = -5/20 V I _D = 10 A Per JEDEC24 pg 27 | Fig. 12 |
| Q _{gd} | Gate to Drain Charge | 13.6 | | | | |
| Q _g | Gate Charge Total | 32.6 | | | | |

Typical Performance

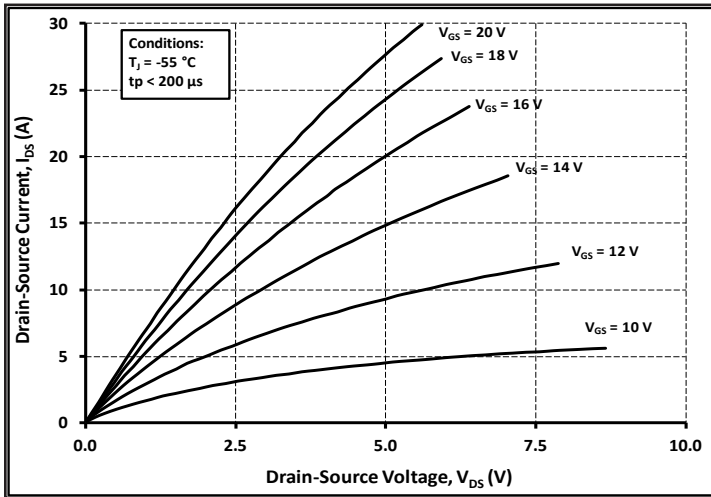


Figure 1. Typical Output Characteristics $T_j = -55\text{ }^\circ\text{C}$

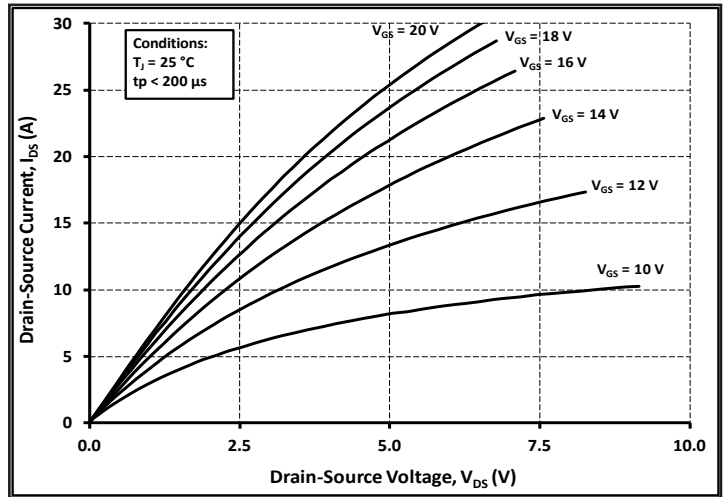


Figure 2. Typical Output Characteristics $T_j = 25\text{ }^\circ\text{C}$

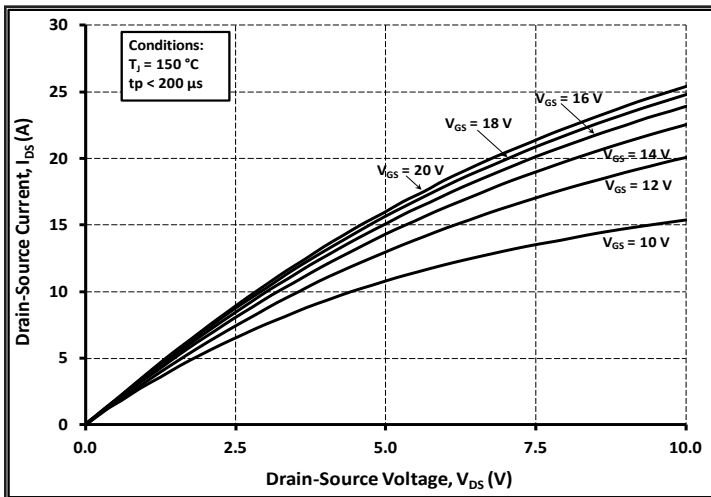


Figure 3. Typical Output Characteristics $T_j = 150\text{ }^\circ\text{C}$

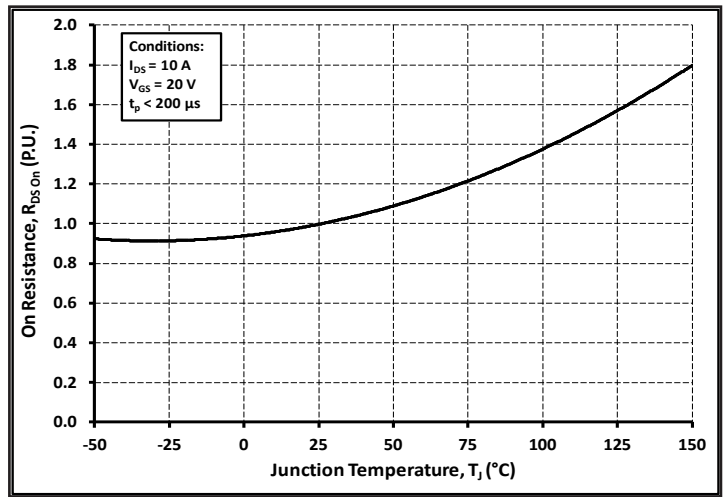


Figure 4. Normalized On-Resistance vs. Temperature

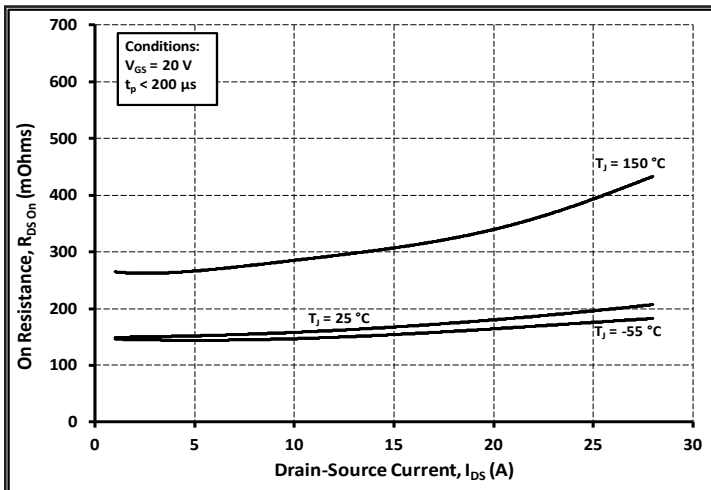


Figure 5. Typical On-Resistance vs. Drain Current For Various Temperatures

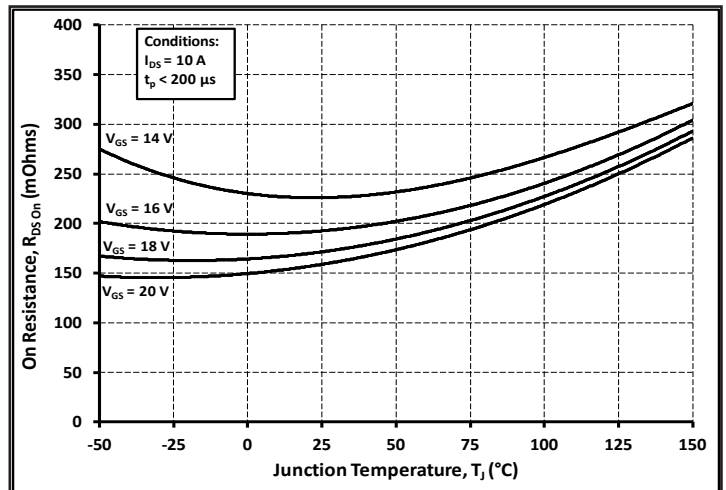


Figure 6. Typical On-Resistance vs. Temperature For Various Gate Voltage

Typical Performance

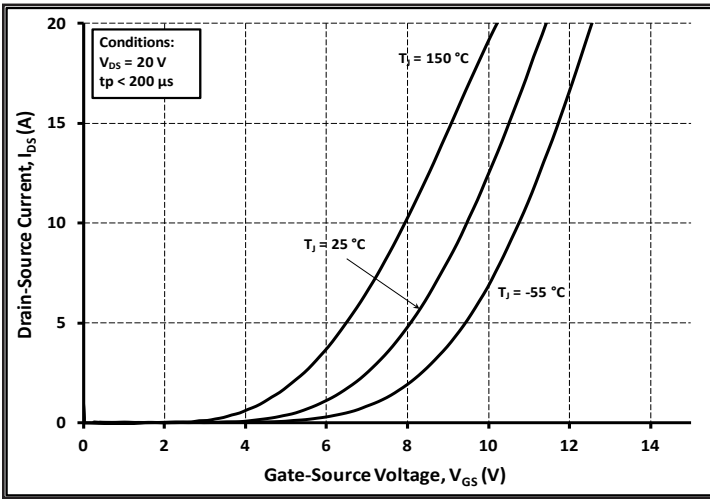


Figure 7. Typical Transfer Characteristic For Various Temperatures

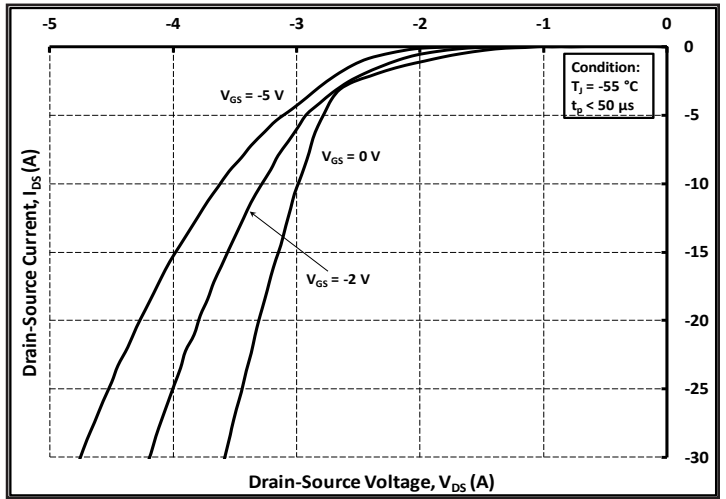


Figure 8. Typical Body Diode Characteristic $T_J = -55\text{ }^\circ\text{C}$

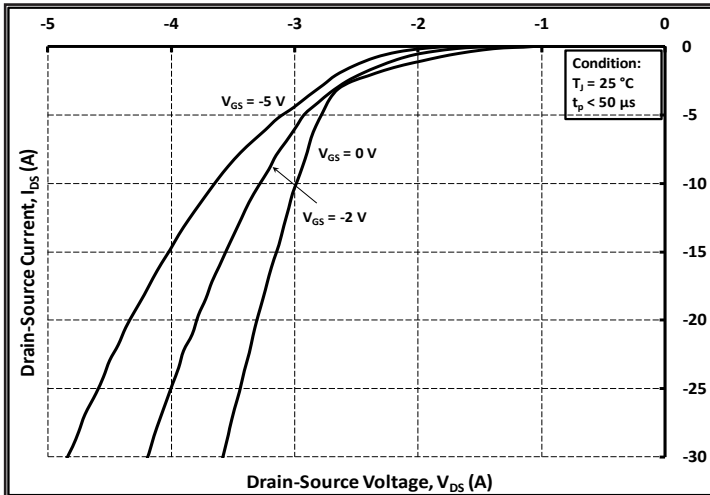


Figure 9. Typical Body Diode Characteristic $T_J = 25\text{ }^\circ\text{C}$

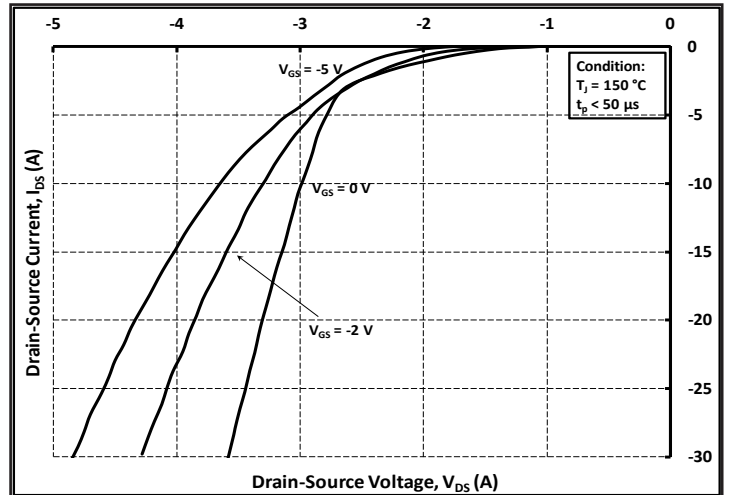


Figure 10. Typical Body Diode Characteristic $T_J = 150\text{ }^\circ\text{C}$

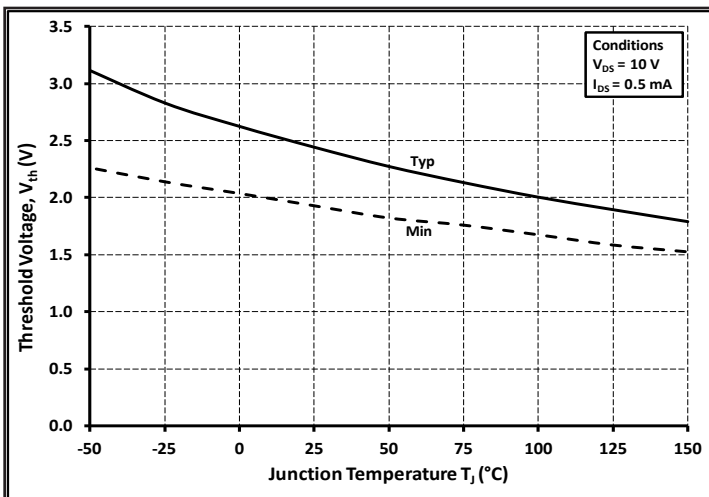


Figure 11. Typical and Minimum Threshold Voltage vs. Temperature

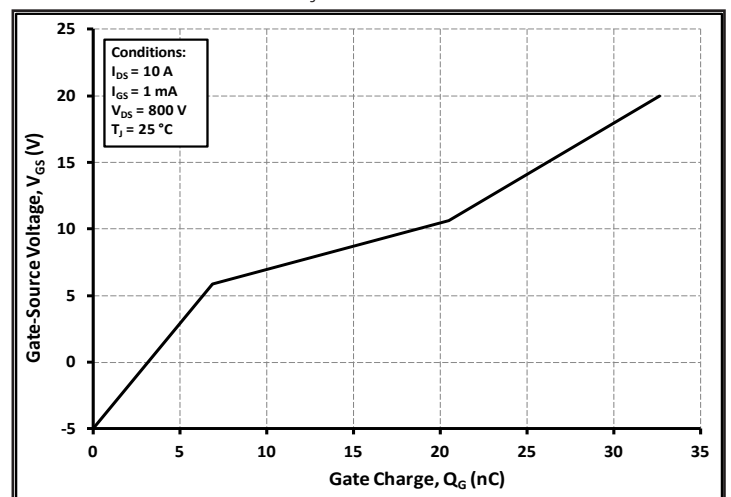


Figure 12. Typical Gate Charge Characteristic 25 °C

Typical Performance

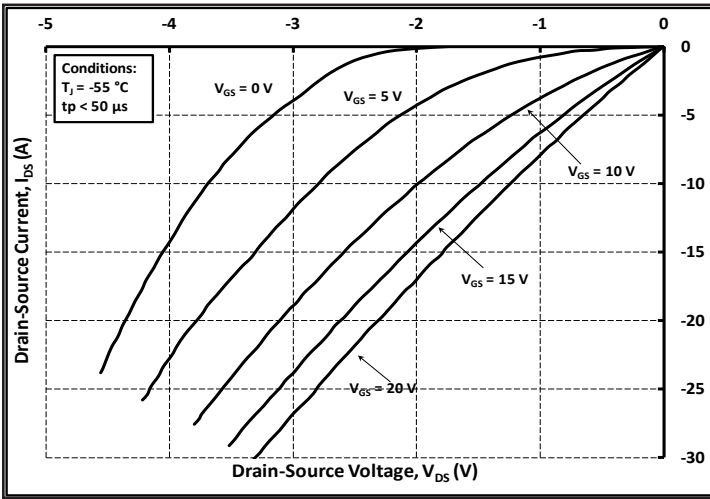


Figure 13. Typical 3rd Quadrant Characteristic
 $T_j = -55\text{ }^\circ\text{C}$

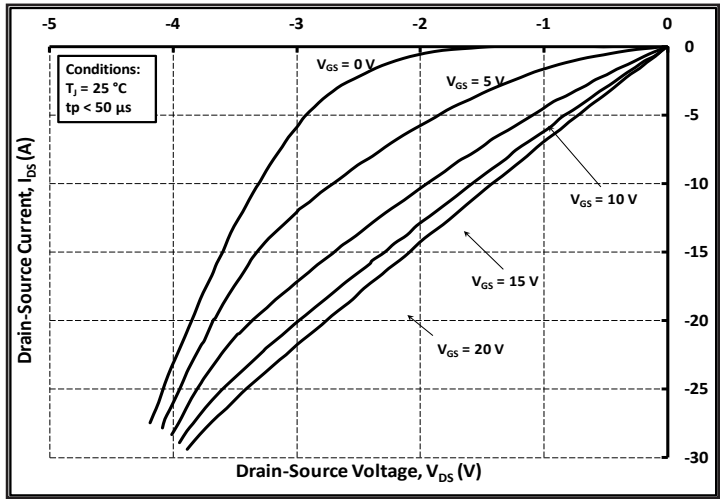


Figure 14. Typical 3rd Quadrant Characteristic
 $T_j = 25\text{ }^\circ\text{C}$

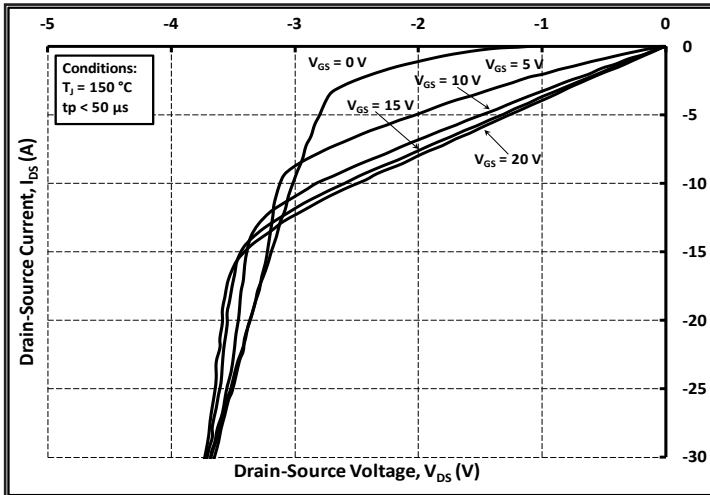


Figure 15. Typical 3rd Quadrant Characteristic
 $T_j = 150\text{ }^\circ\text{C}$

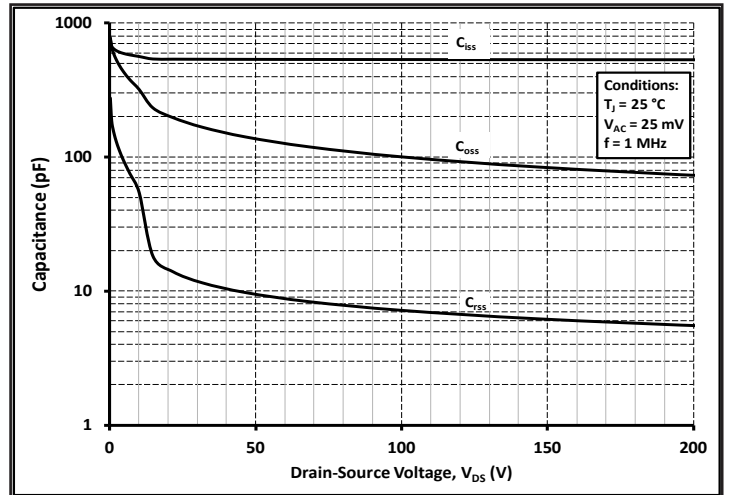


Figure 16. Typical Typical Capacitances vs. Drain-Source Voltage (0 - 200V)

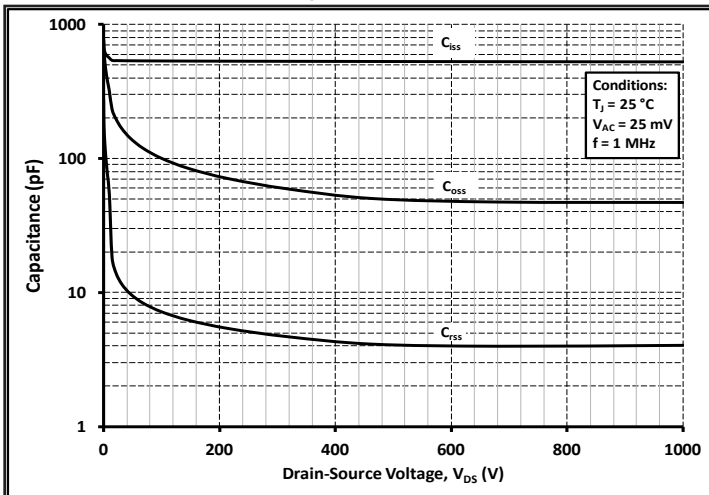


Figure 17. Typical Typical Capacitances vs. Drain-Source Voltage (0 - 1000V)

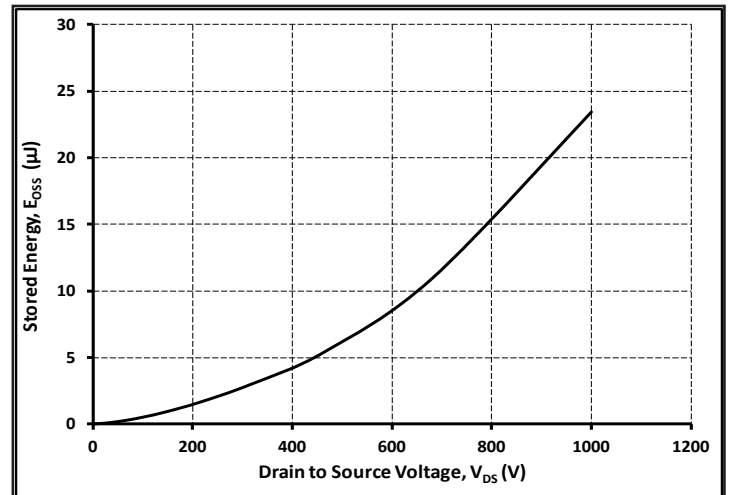


Figure 18. Stored Energy C_{oss}

Typical Performance

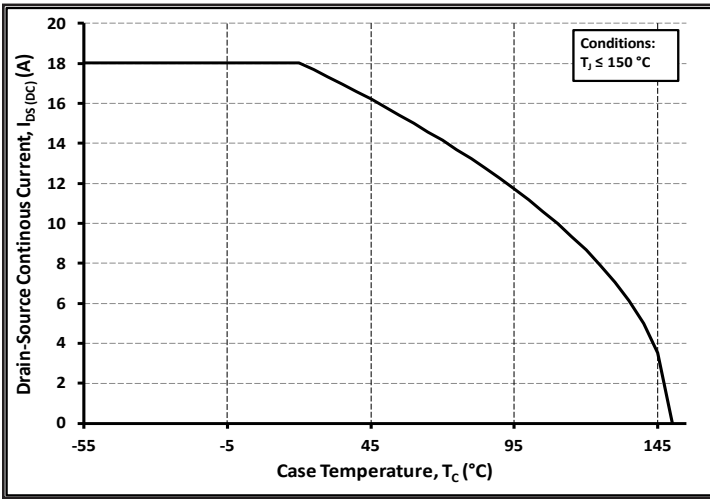


Figure 19. Continuous Current Derating Curve

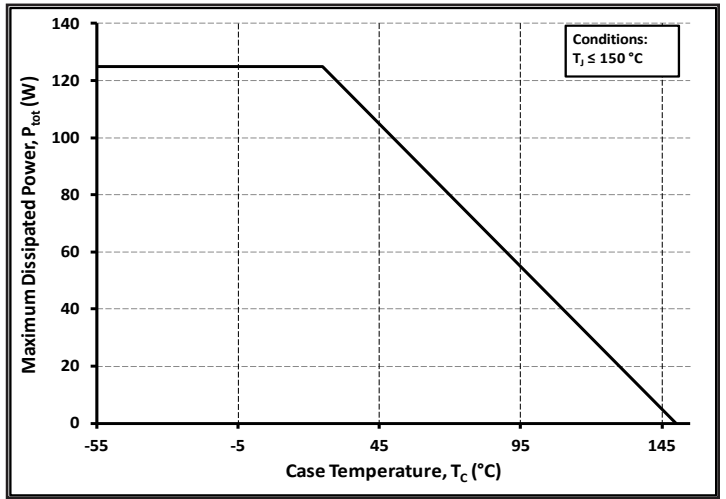


Figure 20. Continuous Power Derating

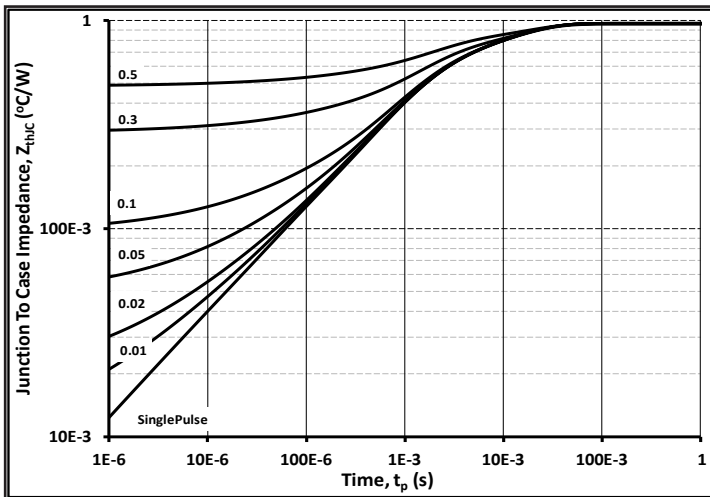


Figure 21. Typical Transient Thermal Impedance (Junction - Case)

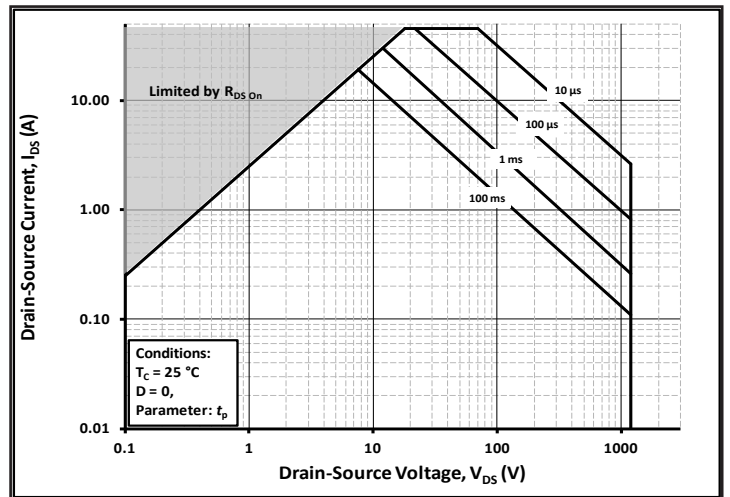


Figure 22. Safe Operating Area

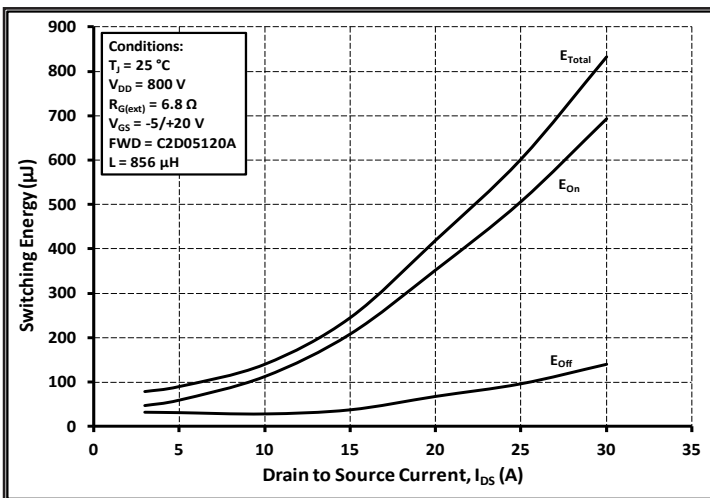


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ($V_{DS} = 800 \text{ V}$)

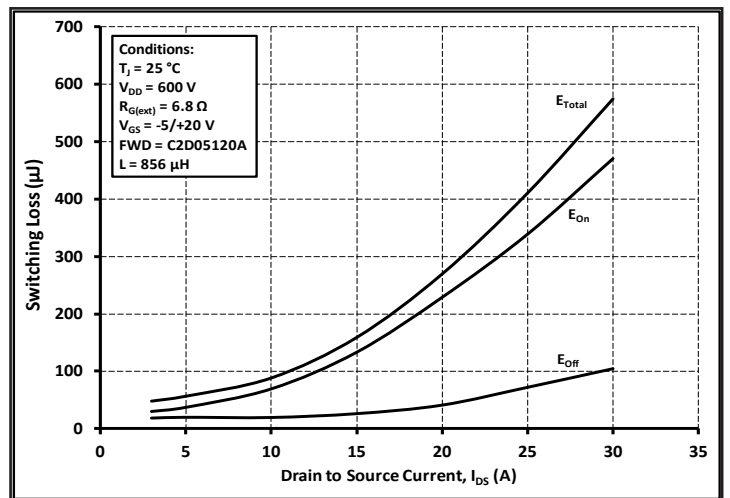


Figure 24. Clamped Inductive Switching Energy vs. Drain Current ($V_{DS} = 600 \text{ V}$)

Typical Performance

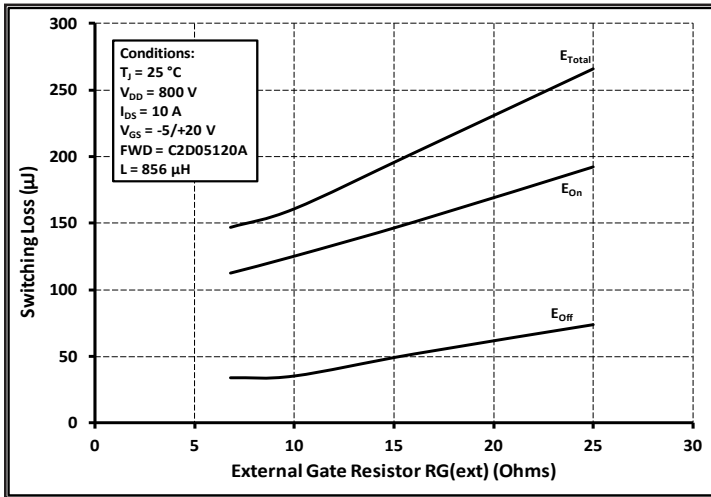


Figure 25. Clamped Inductive Switching Energy vs. $R_{G(\text{ext})}$

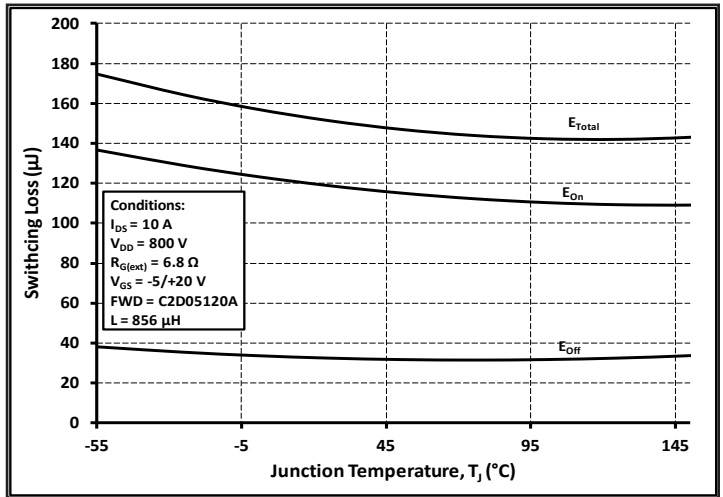


Figure 26. Clamped Inductive Switching Energy vs. Junction Temperature

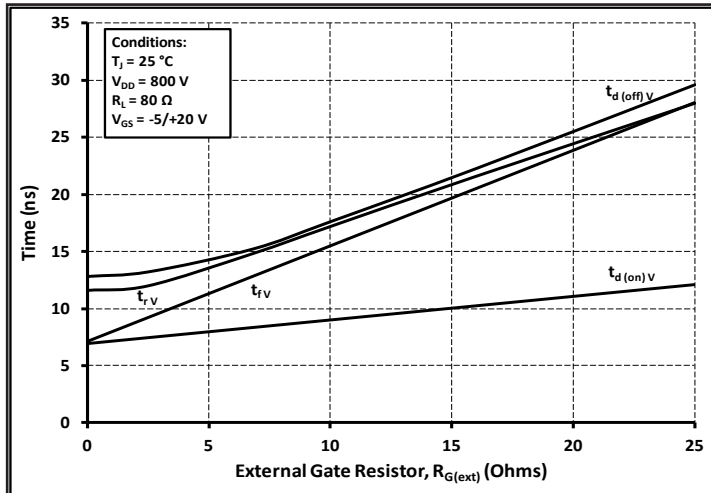


Figure 27. Resistive Switching Times vs. External Gate Resistor ($V_{\text{DD}} = 800\text{ V}$, $I_{\text{D}} = 10\text{ A}$)

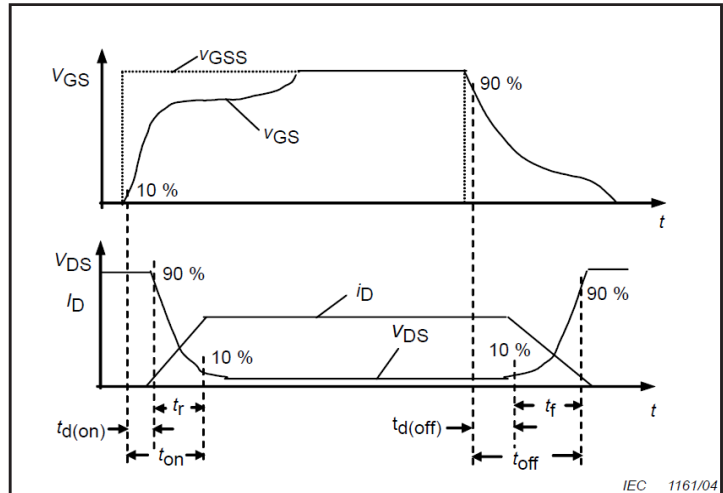


Figure 28. Resistive Switching Time Description

Clamped Inductive Switching Fixture and Waveforms

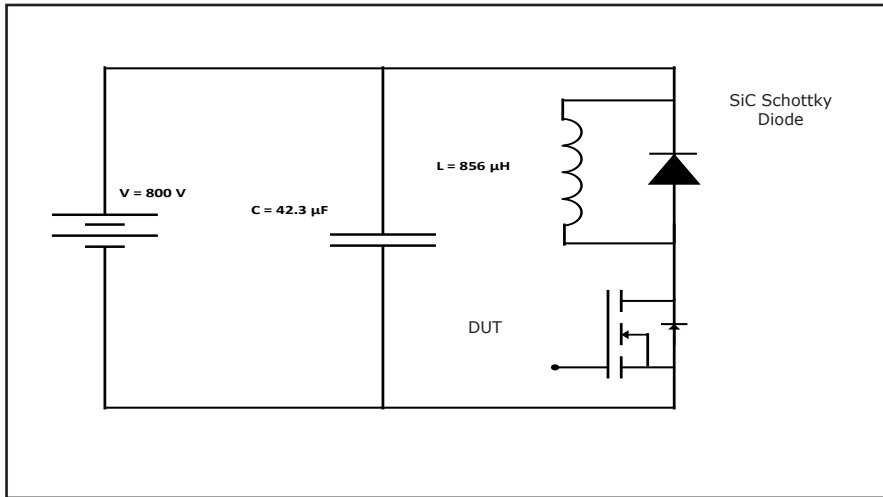


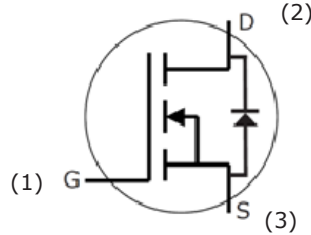
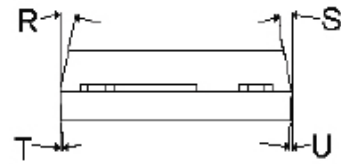
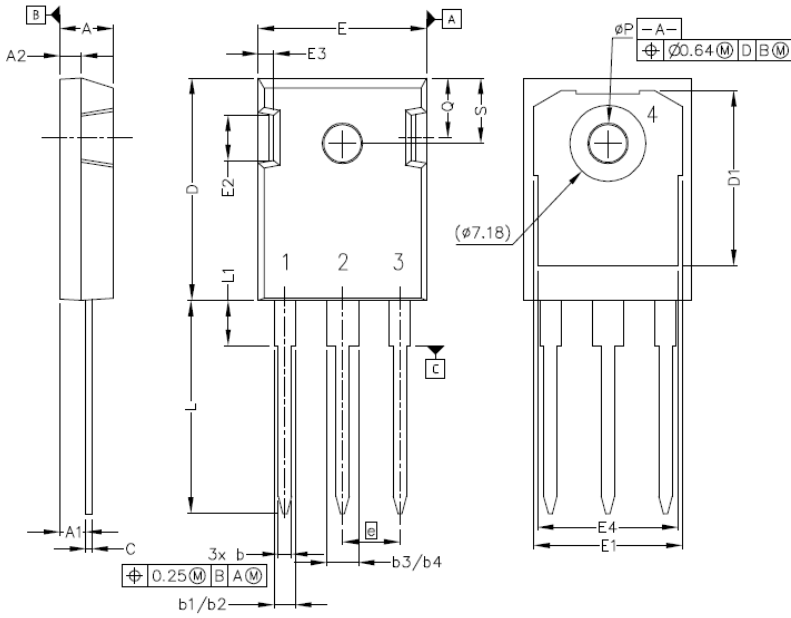
Figure 29. Clamped Inductive Switching Waveform Test Circuit

ESD Ratings

| ESD Test | Total Devices Sampled | Resulting Classification |
|----------|--------------------------|--------------------------|
| ESD-HBM | All Devices Passed 1000V | 2 (>2000V) |
| ESD-MM | All Devices Passed 400V | C (>400V) |
| ESD-CDM | All Devices Passed 1000V | IV (>1000V) |

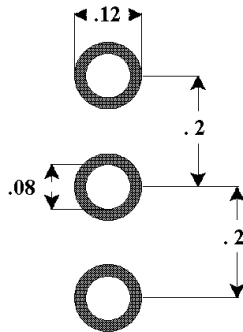
Package Dimensions

Package TO-247-3



| POS | Inches | | Millimeters | |
|-----|----------|------|-------------|-------|
| | Min | Max | Min | Max |
| A | .190 | .205 | 4.83 | 5.21 |
| A1 | .090 | .100 | 2.29 | 2.54 |
| A2 | .075 | .085 | 1.91 | 2.16 |
| b | .042 | .052 | 1.07 | 1.33 |
| b1 | .075 | .095 | 1.91 | 2.41 |
| b2 | .075 | .085 | 1.91 | 2.16 |
| b3 | .113 | .133 | 2.87 | 3.38 |
| b4 | .113 | .123 | 2.87 | 3.13 |
| c | .022 | .027 | 0.55 | 0.68 |
| D | .819 | .831 | 20.80 | 21.10 |
| D1 | .640 | .695 | 16.25 | 17.65 |
| D2 | .037 | .049 | 0.95 | 1.25 |
| E | .620 | .635 | 15.75 | 16.13 |
| E1 | .516 | .557 | 13.10 | 14.15 |
| E2 | .145 | .201 | 3.68 | 5.10 |
| E3 | .039 | .075 | 1.00 | 1.90 |
| E4 | .487 | .529 | 12.38 | 13.43 |
| e | .214 BSC | | 5.44 BSC | |
| N | 3 | | 3 | |
| L | .780 | .800 | 19.81 | 20.32 |
| L1 | .161 | .173 | 4.10 | 4.40 |
| ØP | .138 | .144 | 3.51 | 3.65 |
| Q | .216 | .236 | 5.49 | 6.00 |
| S | .238 | .248 | 6.04 | 6.30 |

Recommended Solder Pad Layout



TO-247-3

| Part Number | Package | Marking |
|-------------|----------|------------|
| C2M0160120D | TO-247-3 | C2M0160120 |

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical equipment, aircraft navigation or communication or control systems, air traffic control systems, or weapons systems.

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